

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Warren M. Farnworth
Alan G. Wood
Trung Tri Doan
David R. Hembree

Art Unit: 2858

Serial No.: 08/838,452 ✓

Filing Date: April 7, 1997 ✓

Examiner: Karlsen, E.

Title: Test Apparatus For Testing
Semiconductor Dice Including
Substrate With Penetration
Limiting Contacts For Making
Electrical Connections
(as amended) ✓

Attorney Docket No.: 91-62.17

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**AMENDMENT
November 11, 1998**

Commissioner of Patents and Trademarks
BOX AMENDMENT (FEE)
Washington, D.C. 20231

Sir:

In response to the Office Action dated August 11, 1998 having a statutory period for response set to expire on November 11, 1998, please amend the captioned case as follows.

In the Specification

Please change the title to --Test Apparatus For Testing Semiconductor Dice Including Substrate With Penetration Limiting Contacts For Making Electrical Connections--.

On page 23, line 18, change "is" to --to be--.